Unit: mm

TOSHIBA Field Effect Transistor Silicon N Channel MOS Type ( $L^2$ - $\pi$ -MOSV)

# 2SK2233

# Chopper Regulator, DC-DC Converter and Motor Drive Applications

• 4-V gate drive

• Low drain-source ON resistance : RDS (ON) =  $0.022 \Omega$  (typ.)

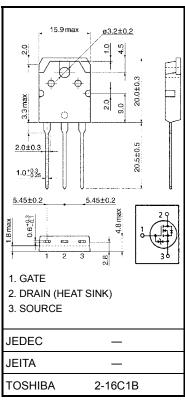
• High forward transfer admittance :  $|Y_{fs}| = 27 \text{ S (typ.)}$ 

• Low leakage current :  $IDSS = 100 \mu A (max) (VDS = 60 V)$ 

• Enhancement mode  $V_{th} = 0.8 \sim 2.0 \text{ V (V}_{DS} = 10 \text{ V, I}_{D} = 1 \text{ mA})$ 

#### Absolute Maximum Ratings (Ta = 25°C)

Characteri	stics	Symbol	Rating	Unit
Drain-source voltage		$V_{DSS}$	60	V
Drain-gate voltage (R <sub>GS</sub> = 20 kΩ)		$V_{DGR}$	60	V
Gate-source voltage		V <sub>GSS</sub>	±20	V
Drain current	DC (Note 1)	I <sub>D</sub>	45	Α
	Pulse (Note 1)	I <sub>DP</sub>	180	Α
Drain power dissipation (Tc = 25°C)		P <sub>D</sub>	100	W
Single pulse avalanche energy (Note 2)		E <sub>AS</sub>	246	mJ
Avalanche current		I <sub>AR</sub>	45	Α
Repetitive avalanche energy (Note 3)		E <sub>AR</sub>	10	mJ
Channel temperature		T <sub>ch</sub>	150	°C
Storage temperature range		T <sub>stg</sub>	-55~150	°C



Weight: 4.6 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

#### Thermal Characteristics

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R <sub>th (ch-c)</sub>	1.25	°C/W
Thermal resistance, channel to ambient	R <sub>th (ch-a)</sub>	50	°C/W

Note 1: Ensure that the channel temperature does not exceed 150°C.

Note 2:  $V_{DD}$  = 25 V,  $T_{ch}$  = 25°C (initial), L = 165  $\mu$ H,  $R_{G}$  = 25  $\Omega$ ,  $I_{AR}$  = 45 A

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device.

Please handle with caution.

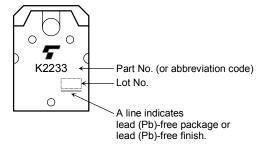
### **Electrical Characteristics (Ta = 25°C)**

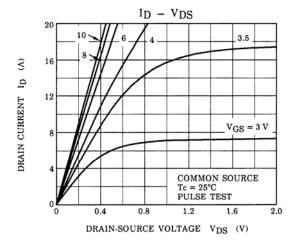
Charac	cteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	ırrent	I <sub>GSS</sub>	V <sub>GS</sub> = ±16 V, V <sub>DS</sub> = 0 V	_	_	±10	μΑ
Drain cut-off cu	rrent	I <sub>DSS</sub>	V <sub>DS</sub> = 60 V, V <sub>GS</sub> = 0 V	_	_	100	μΑ
Drain-source br voltage	reakdown	V (BR) DSS	I <sub>D</sub> = 10 mA, V <sub>GS</sub> = 0 V	60	_	_	٧
Gate threshold v	/oltage	V <sub>th</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 1 mA	0.8	_	2.0	V
Drain-course O	N registance	Б	V <sub>GS</sub> = 4 V, I <sub>D</sub> = 15 A	_	40	55	m0
Drain-source ON resistance	R <sub>DS</sub> (ON)	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 25 A	_	22	30	mΩ	
Forward transfe	r admittance	Y <sub>fs</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 25 A	15	27	_	S
Input capacitano	ce	C <sub>iss</sub>		_	1800	_	
Reverse transfer capacitance  Output capacitance		C <sub>rss</sub>	V <sub>DS</sub> = 10 V, V <sub>GS</sub> = 0 V, f = 1 MHz	_	350	_	pF
		Coss		_	900	_	
R	Rise time	t <sub>r</sub>	V <sub>GS</sub> <sub>0V</sub>		20		
Switching time	Turn-on time	t <sub>on</sub>	R <sub>L</sub> =	l	30	l	ns
_	Fall time	t <sub>f</sub>	4, \( \psi \)		40		118
	Turn-off time	t <sub>off</sub>	$V_{DD} = 30V$ Duty $\leq 1\%$ , $t_w = 10 \mu s$	_	130	_	
Total gate charge (Gate-source plus gate-drain)		Qg			60		
Gate-source charge		Q <sub>gs</sub>	$V_{DD} \approx 48 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 45 \text{ A}$	_	40	_	nC
Gate-drain ("miller") charge		Q <sub>gd</sub>	]		20		

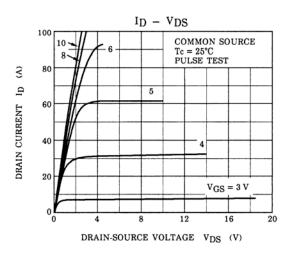
## Source-Drain Ratings and Characteristics (Ta = 25°C)

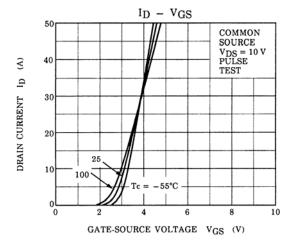
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I <sub>DR</sub>	_	_	_	45	Α
Pulse drain reverse current (Note 1)	I <sub>DRP</sub>	_	_	_	180	Α
Forward voltage (diode)	V <sub>DSF</sub>	I <sub>DR</sub> = 45 A, V <sub>GS</sub> = 0 V	_	_	-1.8	V
Reverse recovery time	t <sub>rr</sub>	I <sub>DR</sub> = 45 A, V <sub>GS</sub> = 0 V	_	90	_	ns
Reverse recovered charge	Q <sub>rr</sub>	dl <sub>DR</sub> / dt = 100 Å / μs	_	0.1	_	μC

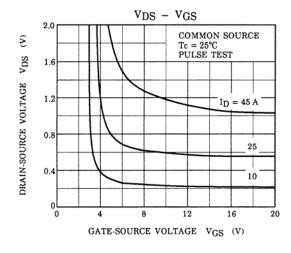
## Marking

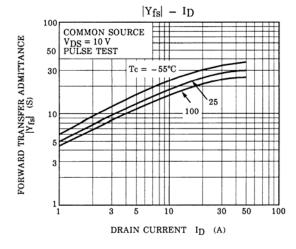


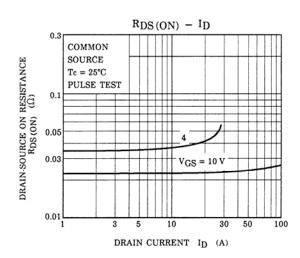


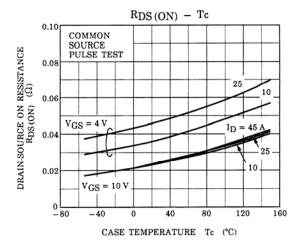


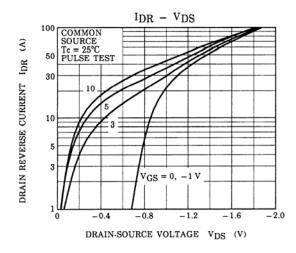


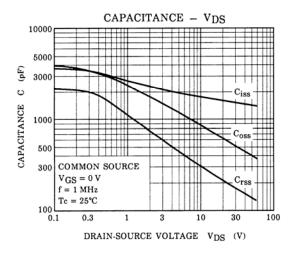


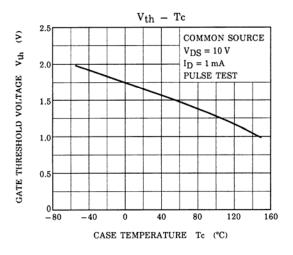


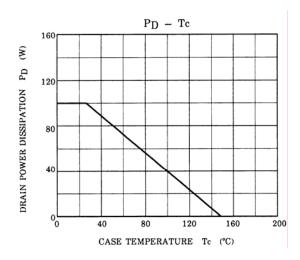


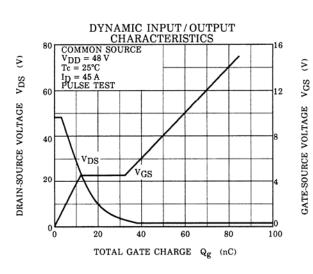


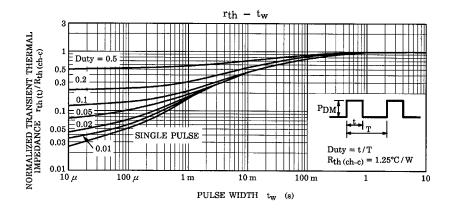


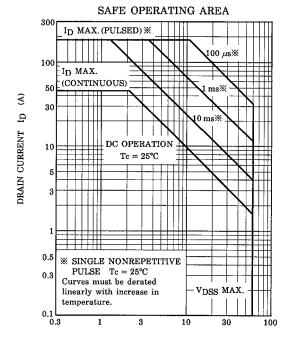


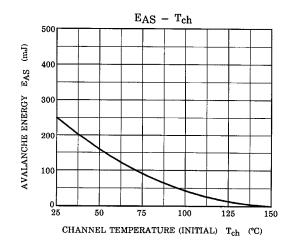


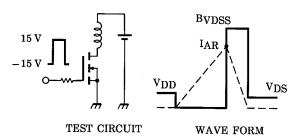












$$\begin{split} R_G &= 25~\Omega \\ V_{DD} &= 25~V,~L = 165~\mu H \end{split}$$

$$E_{AS} = \frac{1}{2} \cdot L \cdot I^{2} \cdot \left( \frac{BVDSS}{BVDSS - VDD} \right)$$

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